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TITLE: Semiconductor device test apparatus

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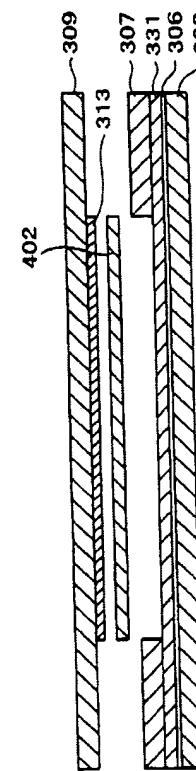


FIG. 22

	Document ID	Kind Codes	Source	Issue Date	Pages	
1	US 6522125 B2		USPAT	20030218	20	Trans
2	US 6484279 B2		USPAT	20021119	17	Test
3	US 6461890 B1		USPAT	20021008	23	Stru
4	US 6433563 B1		USPAT	20020813	30	Prod
	US 6407563 B2		USPAT	20020618	44	Sem
6	US 6357025 B1		USPAT	20020312	11	Test
7	US 6349396 B1		USPAT	20020219	18	Test
8	US 6349396 B1		USPAT	20020219	18	Test

